### MOTOROLA SEMICONDUCTOR TECHNICAL DATA

#### Product Preview

## 64K x 18 Bit BurstRAM™ Synchronous Fast Static RAM With Burst Counter and Self-Timed Write

The MCM67M618 is a 1,179,648 bit synchronous static random access memory designed to provide a burstable, high-performance, secondary cache for the MC68040 and PowerPC™ microprocessors. It is organized as 65,536 words of 18 bits, fabricated using Motorola's high-performance silicon-gate BiCMOS technology. The device integrates input registers, a 2-bit counter, high speed SRAM, and high drive capability outputs onto a single monolithic circuit for reduced parts count implementation of cache data RAM applications. Synchronous design allows precise cycle control with the use of an external clock (K). BiCMOS circuitry reduces the overall power consumption of the integrated functions for greater reliability.

Addresses (A0 – A15), data inputs (DQ0 – DQ17), and all control signals, except output enable (G), are clock (K) controlled through positive-edge-triggered noninverting registers.

Bursts can be initiated with either transfer start processor (TSP) or transfer start cache controller (TSC) input pins. Subsequent burst addresses are generated internally by the MCM67M618 (burst sequence imitates that of the MC68040) and controlled by the burst address advance (BAA) input pin. The following pages provide more detailed information on burst controls.

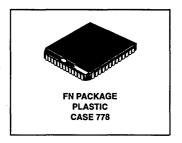
Write cycles are internally self-timed and are initiated by the rising edge of the clock (K) input. This feature eliminates complex off-chip write pulse generation and provides increased flexibility for incoming signals.

Dual write enables ( $\overline{LW}$  and  $\overline{UW}$ ) are provided to allow individually writeable bytes.  $\overline{LW}$  controls DQ0 – DQ8 (the lower bits), while  $\overline{UW}$  controls DQ9 – DQ17 (the upper bits).

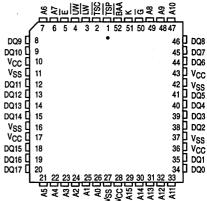
This device is ideally suited for systems that require wide data bus widths and cache memory.

- Single 5 V ± 5% Power Supply
- Fast Access Times: 9/11/14/19 ns Max and Cycle Times: 12.5/15/20/25 ns Min
- · Byte Writeable via Dual Write Strobes
- Internal Input Registers (Address, Data, Control)
- Internally Self-Timed Write Cycle
- TSP, TSC, and BAA Burst Control Pins
- Asynchronous Output Enable Controlled Three-State Outputs
- · Common Data Inputs and Data Outputs
- · High Board Density 52-PLCC Package
- 3.3 V I/O Compatible

#### MCM67M618



#### PIN ASSIGNMENT



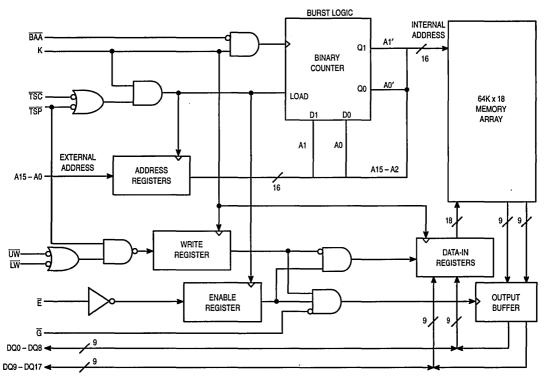
PIN NAMES					
A0 – A15 Address Inputs K					

All power supply and ground pins must be connected for proper operation of the device.

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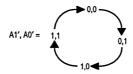
This document contains information on a new product under development. Motorola reserves the right to change or discontinue this product without notice.

#### **BLOCK DIAGRAM** (See Note)



NOTE: All registers are positive-edge triggered. The TSC or TSP signals control the duration of the burst and the start of the next burst. When TSP is sampled low, any ongoing burst is interrupted and a read (independent of \overline{W} and \overline{TSC}) is performed using the new external address. When TSC is sampled low (and TSP is sampled high), any ongoing burst is interrupted and a read or write (dependent on \overline{W}) is performed using the next external address. Chip enable (\overline{E}) is sampled only when a new base address is loaded. After the first cycle of the burst, \overline{BAA} controls subsequent burst cycles. When \overline{BAA} is sampled low, the internal address is advanced prior to the operation. When \overline{BAA} is sampled high, the internal address is not advanced, thus inserting a wait state into the burst sequence accesses. Upon completion of a burst, the address will wrap around to its initial state. See BURST SEQUENCE GRAPH. Write refers to either or both byte write enables (\overline{LW}, \overline{LW}).

#### **BURST SEQUENCE GRAPH (See Note)**



NOTE: The external two values for A1 and A0 provide the starting point for the burst sequence graph. The burst logic advances A1 and A0 as shown above.

#### SYNCHRONOUS TRUTH TABLE (See Notes 1, 2, and 3)

Ē	TSP	TSC	BAA	LW or UW	К	Address	Operation
Н	L	Х	Х	х	L-H	N/A	Deselected
Н	х	L	Х	Х	L-H	N/A	Deselected
L	L	Х	Х	Х	L-H	External Address	Read Cycle, Begin Burst
L	н	L	Х	L	L-H	External Address	Write Cycle, Begin Burst
L	н	L	Х	Н	L-H	External Address	Read Cycle, Begin Burst
Х	Н	Н	L	L	L-H	Next Address	Write Cycle, Continue Burst
Х	Н	Н	L	Н	L-H	Next Address	Read Cycle, Continue Burst
Х	Н	Н	Н	L	L-H	Current Address	Write Cycle, Suspend Burst
Х	Н	Н.	Н	Н	L-H	Current Address	Read Cycle, Suspend Burst

#### NOTES:

- 1. X means Don't Care.
- 2. All inputs except  $\overline{G}$  must meet setup and hold times for the low-to-high transition of clock (K).
- 3. Wait states are inserted by suspending burst.

#### ASYNCHRONOUS TRUTH TABLE (See Notes 1 and 2)

Operation	G	I/O Status
Read	L	Data Out (DQ0 - DQ8)
Read	н	High-Z
Write	×	High-Z — Data In
Deselected	x	High-Z

#### NOTES:

- 1. X means Don't Care.
- 2. For a write operation following a read operation,  $\overline{G}$  must be high before the input data required setup time and held high through the input data hold time.

#### ABSOLUTE MAXIMUM RATINGS (Voltages Referenced to VSS = VSSQ = 0 V)

Rating	Symbol	Value	Unit
Power Supply Voltage	Vcc	- 0.5 to + 7.0	V
Voltage Relative to VSS for Any Pin Except VCC	V <sub>in</sub> , V <sub>out</sub>	- 0.5 to V <sub>CC</sub> + 0.5	٧
Output Current (per I/O)	lout	±30	mA
Power Dissipation	PD	1.6	w
Temperature Under Bias	T <sub>bias</sub>	- 10 to + 85	°C
Operating Temperature	TA	0 to +70	°C
Storage Temperature	T <sub>stg</sub>	- 55 to + 125	°C

NOTE: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to RECOMMENDED OPERATING CONDITIONS. Exposure to higher than recommended voltages for extended periods of time could affect device reliability.

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high-impedance circuit.

This BiCMOS memory circuit has been designed to meet the dc and ac specifications shown in the tables, after thermal equilibrium has been established.

This device contains circuitry that will ensure the output devices are in High-Z at power up.

#### DC OPERATING CONDITIONS AND CHARACTERISTICS

(VCC = 5.0 V  $\pm$  5%, T<sub>A</sub> = 0 to + 70°C, Unless Otherwise Noted)

#### RECOMMENDED OPERATING CONDITIONS (Voltages referenced to V<sub>SS</sub> = 0 V)

Parameter	Symbol	Min	Max	Unit
Supply Voltage (Operating Voltage Range)	Vcc	4.75	5.25	٧
Input High Voltage	VIH	2.2	V <sub>CC</sub> + 0.3**	٧
Input Low Voltage	V <sub>IL</sub>	- 0.5*	0.8	٧

#### DC CHARACTERISTICS AND SUPPLY CURRENTS

Parameter	Symbol	Min	Max	Unit
Input Leakage Current (All Inputs, V <sub>In</sub> = 0 to V <sub>CC</sub> )	likg(i)		± 1.0	μА
Output Leakage Current (G = V <sub>IH</sub> )	l <sub>lkg(O)</sub>	_	± 1.0	μА
AC Supply Current ( $\overline{G}$ = V <sub>IH</sub> , $\overline{E}$ = V <sub>IL</sub> , I <sub>out</sub> = 0 mA, All Inputs = V <sub>IL</sub> or V <sub>IH</sub> , V <sub>IL</sub> = 0.0 V and V <sub>IH</sub> $\geq$ 3.0 V, Cycle Time $\geq$ t <sub>KHKH</sub> min)	ICCA9 ICCA11 ICCA14 ICCA19	_	290 275 250 225	mA
AC Standby Current ( $\overline{E}$ = V <sub>IH</sub> , I <sub>Out</sub> = 0 mA, All Inputs = V <sub>IL</sub> and V <sub>IH</sub> , V <sub>IL</sub> = 0.0 V and V <sub>IH</sub> $\geq$ 3.0 V, Cycle Time $\geq$ t <sub>KHKH</sub> min)	ISB1	-	75	mA
Output Low Voltage (I <sub>OL</sub> = + 8.0 mA)	V <sub>OL</sub>	-	0.4	V
Output High Voltage (IOH = - 4.0 mA)	VOH	2.4	3.3	V

NOTE: Good decoupling of the local power supply should always be used. DC characteristics are guaranteed for all possible 68040 bus cycles.

#### $\textbf{CAPACITANCE} \text{ (f = 1.0 MHz, dV = 3.0 V, T}_{A} = 25^{\circ}\text{C, Periodically Sampled Rather Than 100\% Tested)}$

Parameter	Symbol	Min	Тур	Max	Unit
Input Capacitance (All Pins Except DQ0 – DQ17)	C <sub>in</sub>	_	4	5	pF
Input/Output Capacitance (DQ0 - DQ17)	C <sub>I/O</sub>	_	6	8	pF

<sup>\*</sup> $V_{IL}$  (min) = -0.5 V dc;  $V_{IL}$  (m:n) = -2.0 V ac (pulse width  $\le 20.0$  ns) for  $I \le 20.0$  mA. \*\* $V_{IH}$  (max) =  $V_{CC}$  + 0.3 V dc;  $V_{IH}$  (max) =  $V_{CC}$  + 2.0 V ac (pulse width  $\le 20.0$  ns) for  $I \le 20.0$  mA.

#### **AC OPERATING CONDITIONS AND CHARACTERISTICS**

 $(V_{CC} = 5.0 \text{ V} \pm 5\% \text{ T}_{A} = 0 \text{ to} + 70^{\circ}\text{C}, \text{ Unless Otherwise Noted})$ 

Input Timing Measurement Reference Level 1.5 V	Output Timing Reference Level 1.5 V
Input Pulse Levels 0 to 3.0 V	Output Load See Figure 1A Unless Otherwise Noted
Input Rise/Fall Time 3 ns	

#### READ/WRITE CYCLE TIMING (See Notes 1, 2, and 3) (W refers to either or both byte write enables)

	Symbol		67M618-9 67I		67M6	67M618-11		67M618-14		67M618-19		
Parameter	Standard	Alternate	Min	Max	Min	Max	Min	Max	Min	Max	Unit	Notes
Cycle Time	tkhkh	tcyc	12.5	_	15	_	20	_	25	<del>-</del>	ns	
Clock Access Time	tKHQV	tCD		9	_	11	-	14	_	19	ns	4
Output Enable to Output Valid	tGLQV	<sup>t</sup> OE	_	5		5	_	6	_	7	ns	
Clock High to Output Active	tKHQX1	tDC1	6	_	6		6	_	6	_	ns	
Clock High to Output Change	tKHQX2	tDC2	3	_	3	_	3	_	3	_	ns	
Output Enable to Output Active	t <sub>GLQX</sub>	<sup>t</sup> OLZ	0	-	0	_	0	_	0	-	ns	
Output Disable to Q High-Z	tGHQZ	tonz	2	6	2	6	2	6	2	7	ns	5
Clock High to Q High-Z	tKHQZ	tcz	_	6	_	6	_	6	_	6	ns	5
Clock High Pulse Width	tKHKL	t <sub>CH</sub>	5	_	5	_	6	_	7	_	ns	
Clock Low Pulse Width	tKLKH	tCL	5	<b>—</b>	5	_	6	_	7	_	ns	
Setup Times: Address Address Status Data In Write Address Advance Chip Select	tavkh ttsvkh tdvkh twvkh tbavkh tevkh	tas tss tps tws	2.5	_	2.5	_	2.5	_	3.0	_	ns	6
Hold Times: Address Address Status Data In Write Address Advance Chip Select	tKHAX tKHTSX tKHDX tKHWX tKHBAX tKHBAX	tah tsh tdh twh	0.5	_	0.5	_	0.5		0.5	_	ns	6

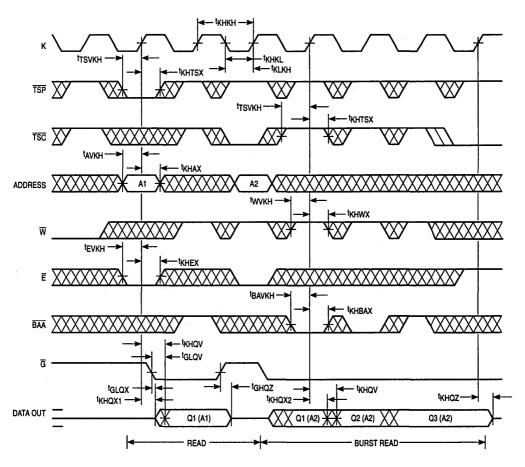
#### NOTES:

- 1. A read cycle is defined by  $\overline{LW}$  and  $\overline{LW}$  high or  $\overline{TSP}$  low for the setup and hold times. A write cycle is defined by  $\overline{LW}$  or  $\overline{LW}$  low and  $\overline{TSP}$  high for the setup and hold times.
- 2. All read and write cycle timings are referenced from K or  $\overline{G}$ .
- 3. G is a don't care when UW or LW is sampled low.
- 4. Maximum access times are guaranteed for all possible MC68040 external bus cycles.
- 5. Transition is measured ± 500 mV from steady-state voltage with load of Figure 1B. This parameter is sampled and not 100% tested. At any given voltage and temperature, tkHQZ max is less than tkHQX1 min for a given device and from device to device.
- 6. This is a synchronous device. All addresses must meet the specified setup and hold times for ALL rising edges of clock (K) whenever TSP or TSC are low and the chip is selected. All other synchronous inputs must meet the specified setup and hold times for ALL rising edges of K when the chip is selected. Chip enable must be valid at each rising edge of clock for the device (when TSP or TSC is low) to remain enabled.

# OUTPUT $= Z_0 = 50 \Omega$ $= Z_0 = 50 \Omega$ OUTPUT $= Z_0 = 50 \Omega$ OUTPUT $= Z_0 = Z_$

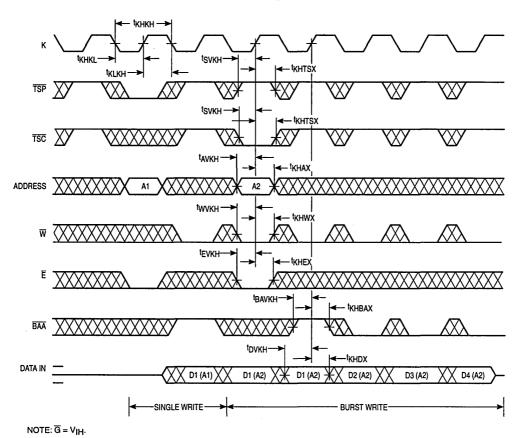
NOTE: For information on output I-V characteristics, see Chapter 8, Section 1.

#### **READ CYCLE**

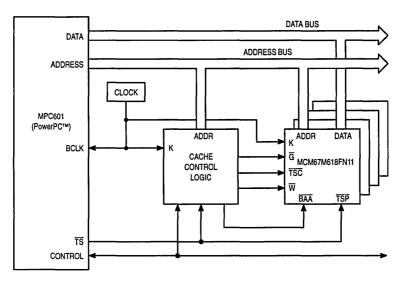


NOTE: Q1(A2) represents the first output from the external address A2; Q2(A2) represents the next output data in the burst sequence with A2 as the base address.

#### **WRITE CYCLE**



#### **APPLICATION EXAMPLE**



512K Byte Burstable, Secondary Cache
Using Four MCM67M618FN11s with a 66 MHz MPC601 PowerPC™

#### ORDERING INFORMATION (Order by Full Part Number)



Full Part Numbers — MCM67M618FN9 MCM67M618FN11 MCM67M618FN14 MCM67M618FN19